

# ACFL-6211U, ACFL-6212U

Bi-directional High-Speed, Low-Power Digital Optocoupler with R<sup>2</sup>Coupler<sup>TM</sup> Isolation in a Stretched 12-Pin Surface-Mount Plastic Package

#### Description

The ACFL-6211U and ACFL-6212U are dual-channel, bi-directional, high-speed digital CMOS optocouplers. The Stretched SO-12 package outline is designed to be compatible with standard surface-mount processes and occupies the same land area as the single-channel Stretched SO-8 package.

This digital optocoupler uses an insulating layer between the light emitting diode and an integrated photodetector to provide electrical insulation between input and output.

Each channel of the digital optocoupler has a CMOS detector IC with an integrated photodiode, a high-speed transimpedance amplifier, and a voltage comparator with an output driver. Each channel is also isolated from the other.

Broadcom R<sup>2</sup>Coupler<sup>™</sup> technology provides reinforced insulation and reliability that deliver safe signal isolation critical in high-temperature industrial applications.

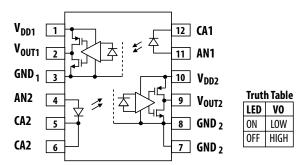
#### Features

- Wide temperature range: -40°C to +125°C
- 5V CMOS compatibility
- 40-kV/µs common-mode rejection at V<sub>CM</sub> = 1000V (typ.)
- Low propagation delay:
  - ACFL-6211U: 25 ns at I<sub>F</sub> = 10 mA (typ.)
  - ACFL-6212U: 60 ns at I<sub>F</sub> = 4 mA (typ.)
- Compact, auto-insertable Stretched SO-12 packages
- Worldwide safety approval:
  - UL 1577 recognized, 5 kV<sub>RMS</sub>/1 min.
  - CSA approved
  - IEC/EN/DIN EN 60747-5-5

#### Applications

- CANBus and SPI communications interface
- High-temperature digital/analog signal isolation
- Power transistor isolation

#### **Functional Diagram**



**NOTE:** Connecting a 1-µF bypass capacitor between pins 1 and 3 and pins 8 and 10 is recommended.

**CAUTION!** It is advised that normal static precautions be taken in handling and assembly of this component to prevent damage and/or degradation that may be induced by ESD. The components featured in this data sheet are not to be used in military or aerospace applications or environments.

#### **Pin Description**

Pin No.	Pin Name	Description	Pin No.	Pin Name	Description
1	V <sub>DD1</sub>	Primary Side Power Supply	7	GND2	Secondary Side Ground
2	V <sub>OUT1</sub>	Output 1	8	GND2	Secondary Side Ground
3	GND1	Primary Side Ground	9	V <sub>OUT2</sub>	Output 2
4	AN2	Anode 2	10	V <sub>DD2</sub>	Secondary Side Power Supply
5	CA2	Cathode 2	11	AN1	Anode 1
6	CA2	Cathode 2	12	CA1	Cathode 1

## **Ordering Information**

Part Number	Option (RoHS Compliant)	Package	Surface Mount	Tape & Reel	UL 5000 V <sub>RMS</sub> / 1-Minute Rating	IEC/EN/DIN EN 60747-5-5	Quantity
ACFL-6211U	-000E	Stretched SO-12	Х		Х		80 per tube
	-060E		Х		Х	Х	80 per tube
	-500E	_	Х	Х	Х		1000 per reel
	-560E	_	Х	Х	Х	Х	1000 per reel
ACFL-6212U	-000E	Stretched SO-12	Х		Х		80 per tube
	-060E	_	Х		Х	Х	80 per tube
	-500E		Х	Х	Х		1000 per reel
	-560E	_	Х	Х	Х	Х	1000 per reel

To order, choose a part number from the Part Number column and combine it with the desired option from the Option column to form an order entry.

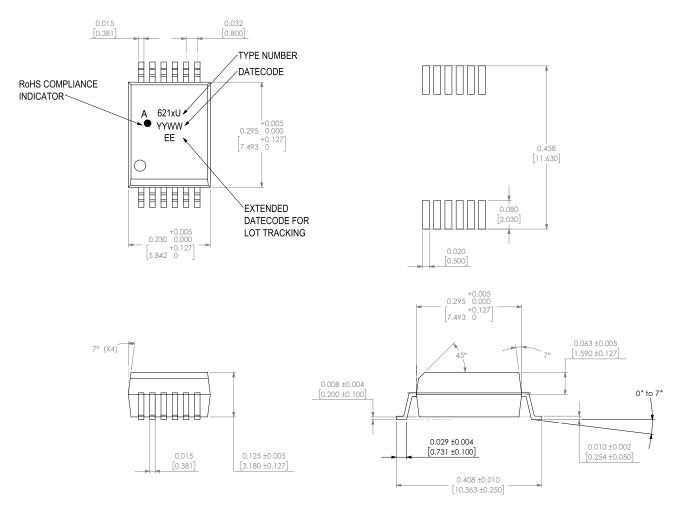
Example 1:

Choose ACFL-6212U-560E to order the product in an SSO-12 surface-mount package in tape and reel packaging with IEC/EN/DIN EN 60747-5-5 safety approval and RoHS compliant.

Option data sheets are available. Contact your Broadcom sales representative or authorized distributor for information.

## Package Outline Drawing

#### Figure 1: ACFL-621xU Package Outline Drawing



Dimensions in inches (millimeters) Lead coplanarity = 0.004 inches (0.1 mm) Mold flash on each side = 0.127 mm (0.005 in.) maximum

#### **Recommended Pb-Free IR Profile**

Recommended reflow condition as per JEDEC standard, J-STD-020 (latest revision).

**NOTE:** Non-halide flux should be used.

## **Regulatory Information**

The ACFL-6211U and ACFL-6212U are approved by the following organizations:

UL	UL 1577, component recognition program up to VISO = 5 kV <sub>RMS</sub>				
CSA Approved under CSA Component Acceptance Notice #5					
IEC/EN/DIN EN 60747-5-5	Approved under IEC/EN/DIN EN 60747-5-5				

#### **Insulation and Safety Related Specifications**

Parameter	Symbol	ACFL-6211U / ACFL-6212U	Units	Conditions
Minimum External Air Gap (Clearance)	L(101)	8.3	mm	Measured from input terminals to output terminals, shortest distance through air.
Minimum External Tracking (Creepage)	L(102)	8.5	mm	Measured from input terminals to output terminals, shortest distance path along body.
Minimum Internal Plastic Gap (Internal Clearance)	—	0.08	mm	Through the insulation distance conductor to the conductor, usually the straight line distance thickness between the emitter and the detector.
Tracking Resistance (Comparative Tracking Index)	CTI	175	V	DIN IEC 112/VDE 0303 Part 1.
Isolation Group (DIN VDE0109)	—	Illa	—	Material Group (DIN VDE 0109).

# IEC/EN/DIN EN 60747-5-5 Insulation-Related Characteristic (Option 060E and 560E)

Description	Symbol	Characteristic	Units
Installation Classification per DIN VDE 0110/1.89, Table 1	_		_
For rated mains voltage ≤ 600 V <sub>RMS</sub>		1-111	
For rated mains voltage < 1000 V <sub>RMS</sub>		1-111	
Climatic Classification	_	40/125/21	
Pollution Degree (DIN VDE 0110/1.89)	—	2	_
Maximum Working Insulation Voltage	V <sub>IORM</sub>	1140	V <sub>PEAK</sub>
Input to Output Test Voltage, Method b	V <sub>PR</sub>	2137	V <sub>PEAK</sub>
$V_{IORM} \times 1.875 = V_{PR}$ , 100% Production Test with $t_m = 1$ sec, Partial Discharge < 5 pC			
Input to Output Test Voltage, Method a	V <sub>PR</sub>	1824	V <sub>PEAK</sub>
$V_{IORM} \times 1.6 = V_{PR}$ , Type and Sample Test, $t_m = 10$ sec, Partial Discharge < 5 pC			
Highest Allowable Overvoltage (Transient Overvoltage, t <sub>ini</sub> = 60 sec)	V <sub>IOTM</sub>	6000	V <sub>PEAK</sub>
Safety Limiting Values (Maximum values allowed in the event of a failure)			
Case Temperature	Τ <sub>S</sub>	175	°C
Input Current	I <sub>S,INPUT</sub>	230	mA
Output Power	P <sub>S,OUTPUT</sub>	600	mW
Insulation Resistance at T <sub>S</sub> , VIO = 500V	RS	10 <sup>9</sup>	Ω

# **Absolute Maximum Ratings**

Parameter	Symbol	Min.	Max.	Units	Condition		
Storage Temperature	Τ <sub>S</sub>	-55	+150	°C			
Ambient Operating Temperature	T <sub>A</sub>	-40	+125	°C			
Junction Temperature	TJ	—	+150	°C			
Supply Voltages	V <sub>DD</sub>	0	6.5	V			
Output Voltage	Vo	-0.5	V <sub>DD</sub> + 0.5	V			
Average Forward Input Current	I <sub>F</sub>	—	20.0	mA			
Peak Transient Input Current (I <sub>F</sub> at 1 µs pulse width, <10% duty cycle)	I <sub>F(TRAN)</sub>	—	1 80	A mA	≤1 µs pulse width, 300 pps ≤1 µs pulse width, <10% duty cycle		
Reverse Input Voltage	V <sub>r</sub>	—	5	V			
Input Power Dissipation	P <sub>I</sub>	_	40	mW			
Average Output Current	lo		10	mA			
Output Power Dissipation	Po	—	30	mW			
Lead Solder Temperature	260°C for 10 sec., 1.6 mm below seating plane.						
Solder Reflow Temperature Profile	See the Solder Reflow Temperature Profile section.						

## **Recommended Operating Conditions**

Parameter	Symbol	Min.	Max.	Units	Note
Supply Voltage	V <sub>DD</sub>	3.0	5.5	V	
Operating Temperature	T <sub>A</sub>	-40	125	°C	
Forward Input Current	I <sub>F(ON)</sub>	4.0	15	mA	
Forward Off State Voltage	V <sub>F(OFF)</sub>		0.8	V	
Input Threshold Current	I <sub>TH</sub>	—	3.5	mA	

#### **Electrical Specifications**

Parameter	Symbol	Min.	Тур.	Max.	Units	Test Conditions	Figure
LED Forward Voltage	V <sub>F</sub>	1.45	1.5	1.75	V	I <sub>F</sub> = 10 mA, T <sub>A</sub> = 25°C	
		1.25	1.5	1.85	V	I <sub>F</sub> = 10 mA	
VF Temperature Coefficient	_	_	-1.5	_	mV/°C	—	
Input Threshold Current	I <sub>TH</sub>	—	1.3	3.5	mA	—	Figure 3
Input Capacitance	C <sub>IN</sub>	—	90	—	pF	—	
Input Reverse Breakdown Voltage	BV <sub>R</sub>	5.0	-	—	V	I <sub>R</sub> = 10 μA	
Logic High Output Voltage	V <sub>OH</sub>	V <sub>DD</sub> – 0.6	—	_	V	I <sub>OH</sub> = -3.2 mA	Figure 5
Logic Low Output Voltage	V <sub>OL</sub>	_	_	0.6	V	I <sub>OL</sub> = 4 mA	Figure 4
Logic Low Output Supply Current (per channel)	I <sub>DDL</sub>	—	0.9	1.5	mA		
Logic High Output Supply Current (per channel)	I <sub>DDH</sub>	—	0.9	1.5	mA	—	

Over recommended operating conditions. All typical specifications are at  $T_A = 25^{\circ}C$ ,  $V_{DD} = 5V$ .

#### ACFL-6211U High-Speed Mode Switching Specifications

Over recommended operating conditions:  $T_A = -40^{\circ}C$  to  $+125^{\circ}C$ ,  $4.5 V \le V_{DD} \le 5.5 V$ . All typical specifications are at  $T_A = 25^{\circ}C$ ,  $V_{DD} = 5V$ .

Parameter	Symbol	Min.	Тур.	Max.	Units	Test Conditions	Figure	Note
Propagation Delay Time to Logic Low Output	t <sub>PHL</sub>	—	25	35	ns	$V_{in} = 4.5V - 5.5V,$ $R_{in} = 390\Omega \pm 5\%,$	Figure 10,	a, b, c
Propagation Delay Time to Logic High Output	t <sub>PLH</sub>	—	25	35	ns	C <sub>in</sub> = 100 pF, CL = 15 pF	Figure 12	
Pulse Width Distortion	PWD	—	0	12	ns	Output low threshold = 0.8V		
Propagation Delay Skew	t <sub>PSK</sub>	_	—	15	ns	Output high threshold = 80% of Vdd		
Output Rise Time (10%–90%)	t <sub>R</sub>	—	10	—	ns			
Output Fall Time (90%–10%)	t <sub>F</sub>	—	10	_	ns			
Common Mode Transient Immunity at Logic High Output	CM <sub>H</sub>	15	25	-	kV/µs	$V_{in} = 0V, R_{in} = 390\Omega \pm 5\%, C_{in} = 100 \text{ pF},$ $V_{cm} = 1000V, T_A = 25^{\circ}C$		d
Common Mode Transient Immunity at Logic Low Output	CM <sub>L</sub>	15	25	-	kV/µs	$V_{in} = 4.5V-5.5V, R_{in} = 390\Omega \pm 5\%,$ $C_{in} = 100 \text{ pF}, V_{cm} = 1000V, T_A = 25^{\circ}\text{C}$		e

a. The t<sub>PHL</sub> propagation delay is measured from the 50% (V<sub>IN</sub> or I<sub>F</sub>) on the rising edge of the input pulse to the 0.8V of V<sub>DD</sub> of the falling edge of the V<sub>O</sub> signal. The t<sub>PLH</sub> propagation delay is measured from the 50% (V<sub>IN</sub> or I<sub>F</sub>) on the falling edge of the input pulse to the 80% level of the rising edge of the V<sub>O</sub> signal.

b. PWD is defined as  $|t_{PHL} - t_{PLH}|$ .

c. t<sub>PSK</sub> is equal to the magnitude of the worst-case difference in t<sub>PHL</sub> and/or t<sub>PLH</sub> that will be seen between units at any given temperature within the recommended operating conditions.

d. CM<sub>H</sub> is the maximum tolerable rate of rise of the common mode voltage to ensure that the output will remain in a high logic state.

e. CM<sub>L</sub> is the maximum tolerable rate of fall of the common mode voltage to ensure that the output will remain in a low logic state.

## ACFL-6212U Low-Power Mode Switching Specifications

Over recommended operating conditions:  $T_A = -40^{\circ}C$  to  $+125^{\circ}C$ ,  $3.0V \le V_{DD} \le 5.5V$ . All typical specifications at 25°C and  $V_{DD} = 5V$ .

Parameter	Symbol	Min.	Тур.	Max.	Units	Test Conditions	Figure	Note
Propagation Delay Time to Logic Low Output	t <sub>PHL</sub>	—	60	100	ns	IF = 4 mA, CL= 15 pF	Figure 8, Figure 13	a, b, c
Propagation Delay Time to Logic High Output	t <sub>PLH</sub>	—	35	100	ns			
Pulse Width Distortion	PWD	—	25	50	ns			
Propagation Delay Skew	t <sub>PSK</sub>	—	—	60	ns			
Output Rise Time (10%–90%)	t <sub>R</sub>	—	10	—	ns			
Output Fall Time (90%–10%)	t <sub>F</sub>	—	10	—	ns			
Common Mode Transient Immunity at Logic High Output	CM <sub>H</sub>	25	40	_	kV/µs	Using Broadcom LED Driving Circuit, $V_{IN} = 0V$ , R1 = 330 $\Omega \pm 5\%$ , R2 = 330 $\Omega \pm 5\%$ , $V_{CM} = 1000V$ , T <sub>A</sub> = 25°C		d
Common Mode Transient Immunity at Logic Low Output	CM <sub>L</sub>	25	40		kV/µs	Using Broadcom LED Driving Circuit, $V_{IN} = 4.5V - 5.5V$ , R1 = 330 $\Omega \pm 5\%$ , R2 = 330 $\Omega \pm 5\%$ , $V_{CM} = 1000V$ , T <sub>A</sub> = 25°C		e

a. The t<sub>PHL</sub> propagation delay is measured from the 50% (V<sub>IN</sub> or I<sub>F</sub>) on the rising edge of the input pulse to the 0.8V of V<sub>DD</sub> of the falling edge of the V<sub>O</sub> signal. The t<sub>PLH</sub> propagation delay is measured from the 50% (V<sub>IN</sub> or I<sub>F</sub>) on the falling edge of the input pulse to the 80% level of the rising edge of the V<sub>O</sub> signal.

b. PWD is defined as  $|t_{PHL} - t_{PLH}|$ .

- c. t<sub>PSK</sub> is equal to the magnitude of the worst-case difference in t<sub>PHL</sub> and/or t<sub>PLH</sub> that will be seen between units at any given temperature within the recommended operating conditions.
- d. CM<sub>H</sub> is the maximum tolerable rate of rise of the common mode voltage to ensure that the output will remain in a high logic state.
- e. CML is the maximum tolerable rate of fall of the common mode voltage to ensure that the output will remain in a low logic state.

## **Package Characteristics**

All typical at  $T_A = 25^{\circ}C$ .

Parameter	Symbol	Min.	Тур.	Max.	Units	Test Conditions	Note
Input-Output Momentary Withstand Voltage	V <sub>ISO</sub>	5000	_	—	V <sub>RMS</sub>	RH ≤ 50%, t = 1 min, T <sub>A</sub> = 25°C	a, b
Input-Output Resistance	R <sub>I-O</sub>		10 <sup>14</sup>		Ω	V <sub>I-O</sub> = 500 V dc	а
Input-Output Capacitance	C <sub>I-O</sub>		0.6		pF	f = 1 MHz, T <sub>A</sub> = 25°C	а

a. Device considered a two terminal device: pins 1 to 6 shorted together, and pins 7 to 12 shorted together.

b. In accordance with UL 1577, each optocoupler is proof tested by applying an insulation test voltage > 6000 V<sub>RMS</sub> for 1 second.

#### Figure 2: Typical Diode Input Forward Current Characteristic

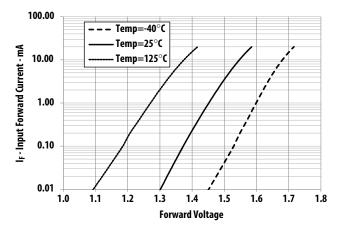


Figure 4: Typical Logic Low Output Voltage vs Logic Low Output Current

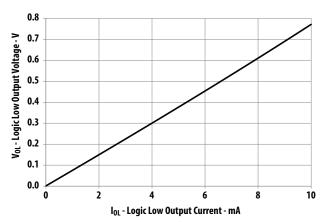
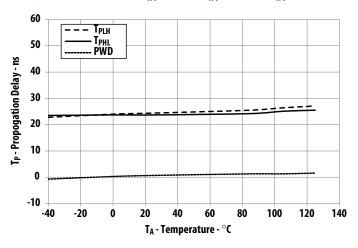
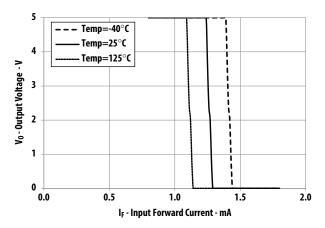
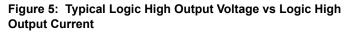


Figure 6: ACFL-6211U (High-Speed) Typical Propagation Delay vs Temperature,  $V_{IN}$  = 4.5V,  $R_{IN}$  = 390 $\Omega$ ,  $C_{IN}$  = 100 pF









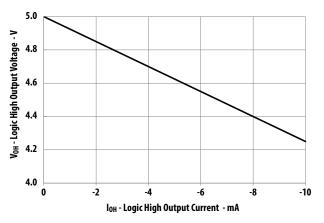
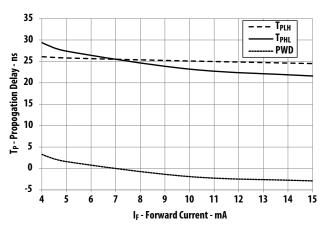


Figure 7: ACFL-6211U (High-Speed) Typical Propagation Delay vs Input Forward Current,  $V_{IN}$  = 4.5V,  $R_{IN}$  = 390 $\Omega$ ,  $C_{IN}$  = 100 pF,  $T_A$  = 25°C



# Figure 8: ACFL-6212U (5V) Typical Propagation Delay vs Temperature

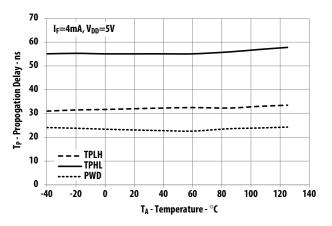


Figure 10: ACFL-6212U (3V) Typical Propagation Delay vs Temperature

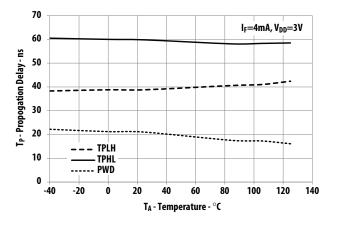
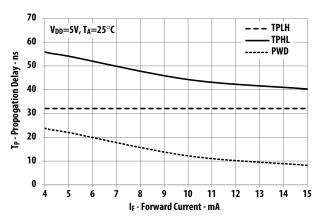
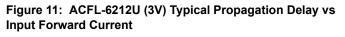
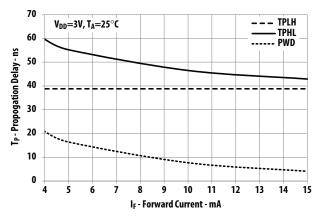
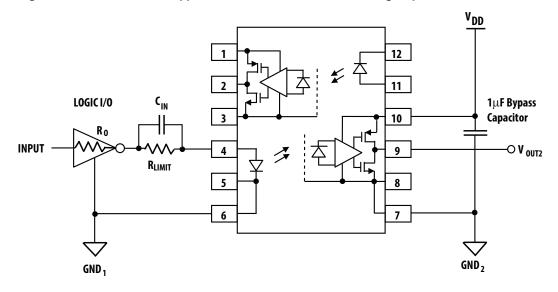


Figure 9: ACFL-6212U (5V) Typical Propagation Delay vs Input Forward Current









#### Figure 12: Recommended Application Circuit for ACFL-6211U High-Speed Performance

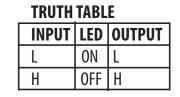
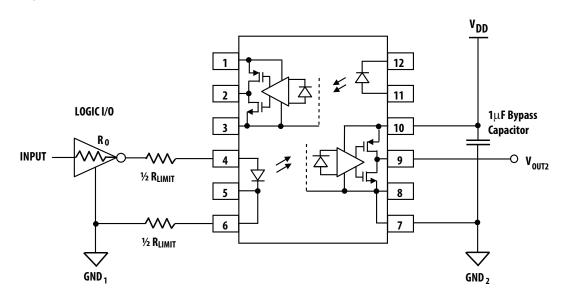


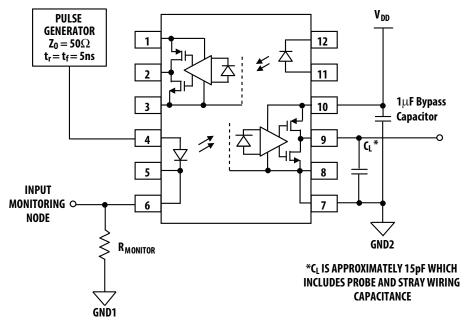
Figure 13: Recommended Application Circuit for ACFL-6212U Low-Power Performance



TRUTH TABLE								
INPUT	LED	OUTPUT						
L	ON	L						
Н	OFF	Н						

#### **Test Circuits**

Figure 14: Test Circuit for t<sub>PHL</sub>, t<sub>PLH</sub>, t<sub>F</sub>, and t<sub>R</sub>



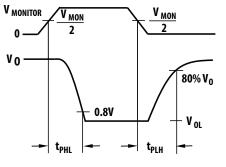
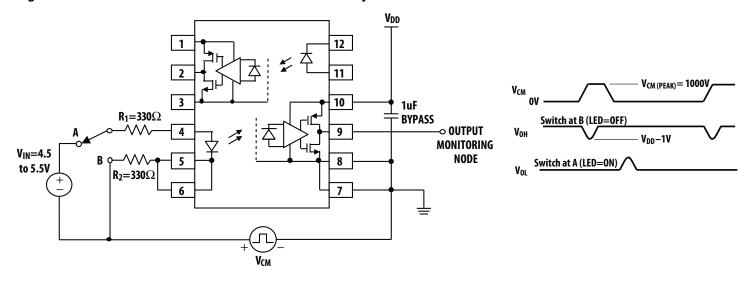


Figure 15: Test Circuit for Common Mode Transient Immunity



#### **Thermal Resistance Measurement**

Figure 16 shows the ACFL-6211U/6212U diagram for measurement. This is a multichip package with four heat sources; the effect of heating of one die due to the adjacent dice are considered by applying the theory of linear superposition. Here, one die is heated first and the temperatures of all the dice are recorded after thermal equilibrium is reached. Then, the second die is heated and all the dice temperatures are recorded and so on until the fourth die is heated. With the known ambient temperature, die junction temperature, and power dissipation, the thermal resistance can be calculated. The thermal resistance calculation can be cast in matrix form. This yields a 4-by-4 matrix for our case of two heat sources.

R11	R12	R13	R14		P1		ΔT1	l
R21	R22	R23	R24		P2		$\Delta T2$	
R31	R32	R33	R34	•	P3	=	$\Delta T3$	
R41	R42	R43	R44		P4		$\Delta T4$	

 $R_{11}$ : Thermal Resistance of Die1 due to heating of Die1 (°C/W)  $R_{12}$ : Thermal Resistance of Die1 due to heating of Die2 (°C/W)  $R_{13}$ : Thermal Resistance of Die1 due to heating of Die3 (°C/W)  $R_{14}$ : Thermal Resistance of Die1 due to heating of Die4 (°C/W)

 $R_{21}$ : Thermal Resistance of Die2 due to heating of Die1 (°C/W)  $R_{22}$ : Thermal Resistance of Die2 due to heating of Die2 (°C/W)  $R_{23}$ : Thermal Resistance of Die2 due to heating of Die3 (°C/W)  $R_{24}$ : Thermal Resistance of Die2 due to heating of Die4 (°C/W)

 $R_{31}$ : Thermal Resistance of Die3 due to heating of Die1 (°C/W)  $R_{32}$ : Thermal Resistance of Die3 due to heating of Die2 (°C/W)  $R_{33}$ : Thermal Resistance of Die3 due to heating of Die3 (°C/W)  $R_{34}$ : Thermal Resistance of Die3 due to heating of Die4 (°C/W)

 $R_{41}$ : Thermal Resistance of Die4 due to heating of Die1 (°C/W)  $R_{42}$ : Thermal Resistance of Die4 due to heating of Die2 (°C/W)  $R_{43}$ : Thermal Resistance of Die4 due to heating of Die3 (°C/W)  $R_{44}$ : Thermal Resistance of Die4 due to heating of Die4 (°C/W)

P1: Power dissipation of Die1 (W)

- P<sub>2</sub>: Power dissipation of Die2 (W)
- P<sub>3</sub>: Power dissipation of Die3 (W)
- P<sub>4</sub>: Power dissipation of Die4 (W)

T<sub>1</sub>: Junction temperature of Die1 due to heat from all dice (°C) T<sub>2</sub>: Junction temperature of Die2 due to heat from all dice (°C)

T<sub>3</sub>: Junction temperature of Die3 due to heat from all dice (°C)

T<sub>4</sub>: Junction temperature of Die4 due to heat from all dice (°C)

Ta: Ambient temperature.

 $\Delta T_1$ : Temperature difference between Die1 junction and ambient (°C)

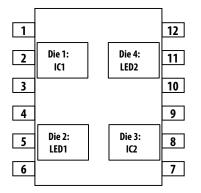
 $\Delta T_2$ : Temperature deference between Die2 junction and ambient (°C)

 $\Delta T_3$ : Temperature difference between Die3 junction and ambient (°C)

 $\Delta T_4$ : Temperature deference between Die4 junction and ambient (°C)

 $\begin{array}{l} T_1 = (R_{11} \times P_1 + R_{12} \times P_2 + R_{13} \times P_3 + R_{14} \times P_4) + Ta - (1) \\ T_2 = (R_{21} \times P_1 + R_{22} \times P_2 + R_{23} \times P_3 + R_{24} \times P_4) + Ta - (2) \\ T_3 = (R_{31} \times P_1 + R_{32} \times P_2 + R_{33} \times P_3 + R_{34} \times P_4) + Ta - (3) \\ T_4 = (R_{41} \times P_1 + R_{42} \times P_2 + R_{43} \times P_3 + R_{44} \times P_4) + Ta - (4) \end{array}$ 

#### Figure 16: Diagram of ACFL-6211U/6212U for Measurement



Measurement data on a low K (conductivity) board:

R<sub>11</sub> = 181°C/W R<sub>21</sub> = 103°C/W R<sub>31</sub> = 82°C/W R<sub>41</sub> = 110°C/W R<sub>12</sub> = 91°C/W R<sub>22</sub> = 232°C/W R<sub>32</sub> = 97°C/W R<sub>42</sub> = 86°C/W R<sub>13</sub> = 85°C/W R<sub>23</sub> = 109°C/W R<sub>33</sub> = 180°C/W R<sub>43</sub> = 101°C/W R<sub>14</sub> = 112°C/W  $R_{24} = 91^{\circ}C/W$ R<sub>34</sub> = 91°C/W R<sub>44</sub> = 277°C/W

#### Measurement data on a high K (conductivity) board:

R <sub>11</sub> = 117°C/W
R <sub>21</sub> = 37°C/W
R <sub>31</sub> = 35°C/W
$R_{41} = 47^{\circ}C/W$
R <sub>12</sub> = 42°C/W
R <sub>22</sub> = 161°C/W
R <sub>32</sub> = 53°C/W
R <sub>42</sub> = 30°C/W
R <sub>13</sub> = 32°C/W
R <sub>23</sub> = 39°C/W
R <sub>33</sub> = 114°C/W
R <sub>43</sub> = 29°C/W
R <sub>14</sub> = 60°C/W
R <sub>24</sub> = 33°C/W
$R_{34}^{-} = 34^{\circ}C/W$
R <sub>44</sub> = 189°C/W

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